UV Cure Characterization for Ion Implantation

Janet Shen, Cornell University

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UV bake processes have been developed to allow resist to withstand ion implantations that use high energy and/or high beam current. All UV cure recipes were tested to withstand 170 uA, 100 keV implantations of 1e15 As.

Three i-line photoresists have been characterized. Two are used with the contact aligner (SPR 220-3.0 and STR1813), while one is used with the 5X Autostep (AS200). The table below lists the spin speeds and bake procedures that are used in the steps: spin, softbake, expose, post-exposure bake (in some cases), develop, UV bake. The photoresists can be removed following ion implantation with 40 minutes in the photoresist hot strip baths. Bathing in acetone overnight does not remove the photoresist.

Photoresist	PR Spin	Softbake	Post	Exposure	Thickness
	Speed		exposure		
			bake (PEB)		
SPR 220-3.0	(4000 rpm,	90 s @ 115	90 s @ 115	102	1.2 um
	1000 rpm/s,	C	С	mJ/cm ²	
	30 s)			(ABM)	
STR 1813	(3000 rpm,	60 s @ 115		150	1.46 um
	1000 rpm/s,	C		mJ/cm ²	
	30 s)			(ABM)	
SPR 955-0.9	(3000 rpm,	90 s @ 90 C	90 s @ 115	0.19 s	0.7872 um
	1000 rpm/s,		C	exposure	
	30 s)			on AS 200	

UV Bake Recipes

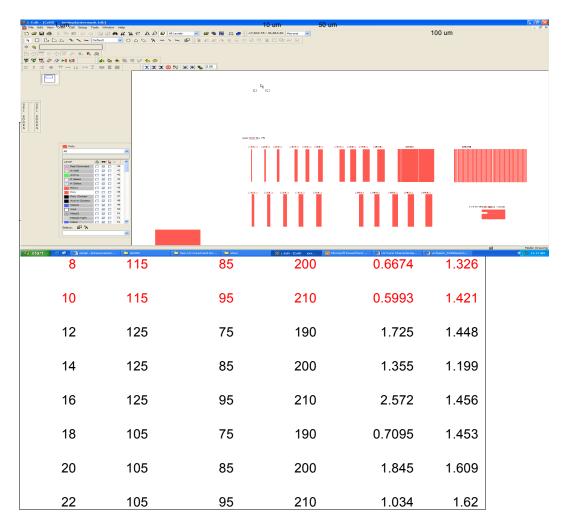
Standard

Temp	Time (s)	Step	Lamp	Time
Softbake		IDLE		
HOLD	5	1	LOW	5
Tfinal	Time_r	2	HIGH	Time_r

Single Flash

Temp	Time (s)	Step	Lamp	Time
Softbake		IDLE		
HOLD	17	1	FLASH	2.0
Tfinal	Time_r	2	OFF	10
		3	LOW	5
		4	HIGH	Time_r

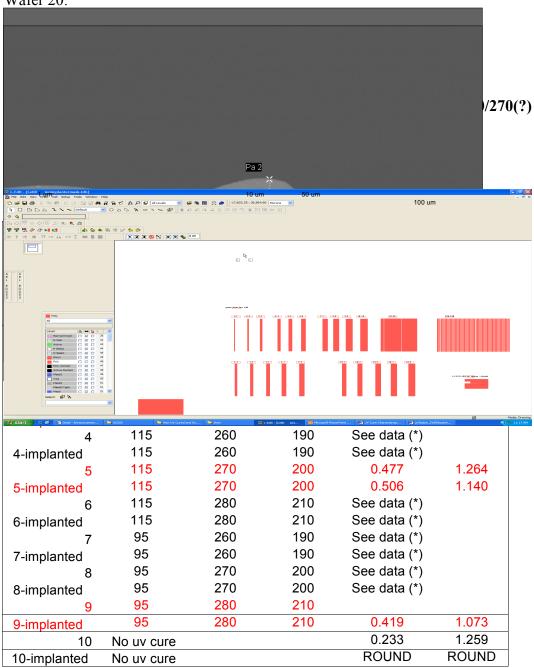
STR1813 Contact Aligner (ABM/EV 620) Mask File



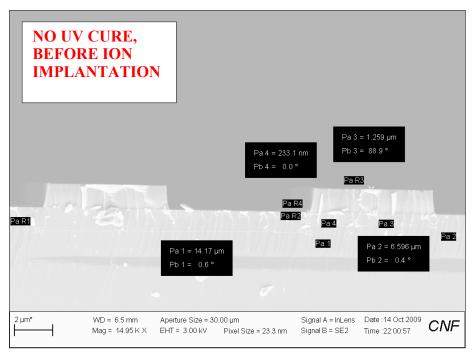
Wafer 18 (SB = 105 C, Ramp = 75 s, T_{final} = 190 C):

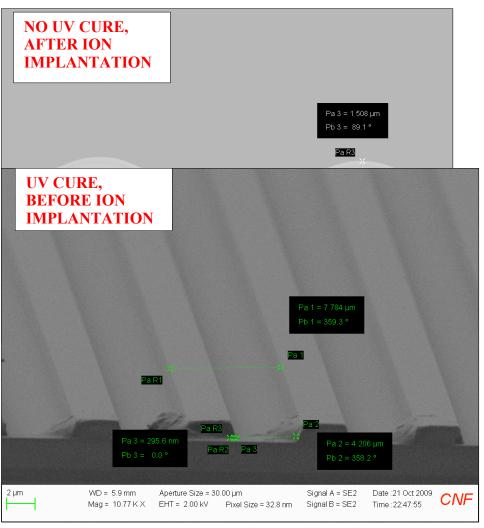


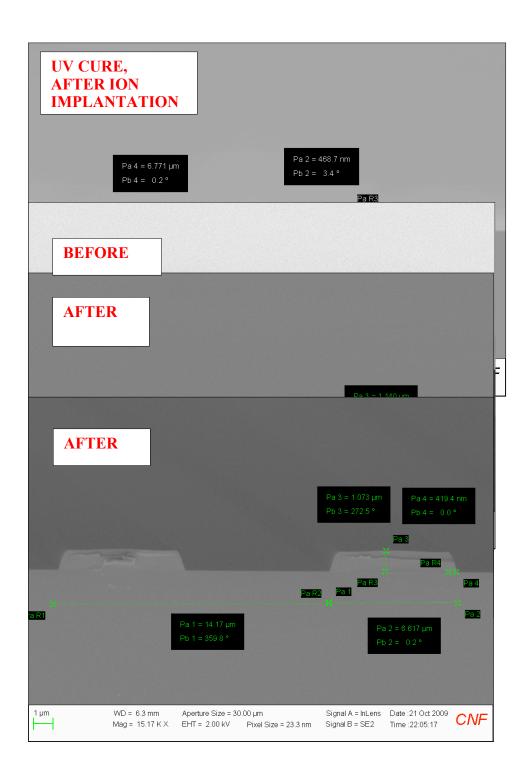
Wafer 20:



Wafer 10 before and after Ion Implantation: NO UV CURE







SPR 955-0.9 UV Cure Recipe: Standard with softbake = 90 C, Time_r = 55 seconds to 200 C Tfinal temperature

